Intel - EPF81500ARC240-2 Datasheet

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	162
Number of Logic Elements/Cells	1296
Total RAM Bits	-
Number of I/O	181
Number of Gates	16000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	240-BFQFP Exposed Pad
Supplier Device Package	240-RQFP (32x32)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epf81500arc240-2

Normal Mode

The normal mode is suitable for general logic applications and wide decoding functions that can take advantage of a cascade chain. In normal mode, four data inputs from the LAB local interconnect and the carry-in signal are the inputs to a 4-input LUT. Using a configurable SRAM bit, the MAX+PLUS II Compiler automatically selects the carry-in or the `DATA3` signal as an input. The LUT output can be combined with the cascade-in signal to form a cascade chain through the cascade-out signal. The `LE-Out` signal—the data output of the LE—is either the combinatorial output of the LUT and cascade chain, or the data output (`Q`)of the programmable register.

Arithmetic Mode

The arithmetic mode offers two 3-input LUTs that are ideal for implementing adders, accumulators, and comparators. One LUT provides a 3-bit function; the other generates a carry bit. As shown in Figure 6, the first LUT uses the carry-in signal and two data inputs from the LAB local interconnect to generate a combinatorial or registered output. For example, in an adder, this output is the sum of three bits: `a`, `b`, and the carry-in. The second LUT uses the same three signals to generate a carry-out signal, thereby creating a carry chain. The arithmetic mode also supports a cascade chain.

Up/Down Counter Mode

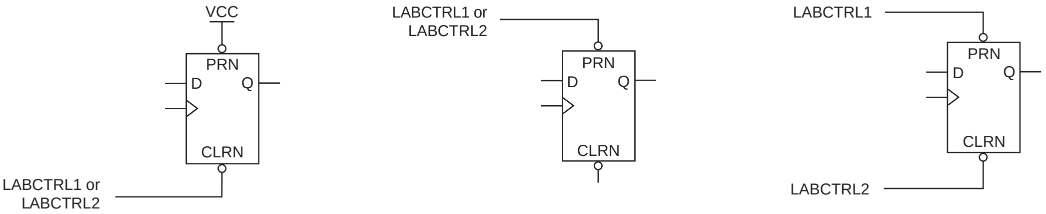
The up/down counter mode offers counter enable, synchronous up/down control, and data loading options. These control signals are generated by the data inputs from the LAB local interconnect, the carry-in signal, and output feedback from the programmable register. Two 3-input LUTs are used: one generates the counter data, and the other generates the fast carry bit. A 2-to-1 multiplexer provides synchronous loading. Data can also be loaded asynchronously with the clear and preset register control signals, without using the LUT resources.

Clearable Counter Mode

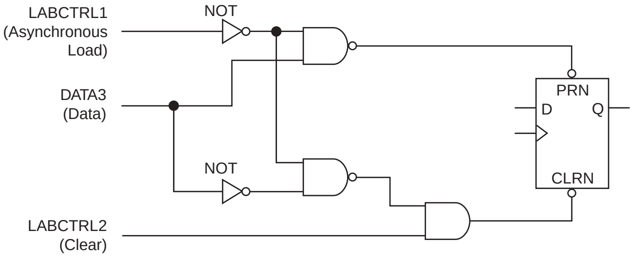
The clearable counter mode is similar to the up/down counter mode, but supports a synchronous clear instead of the up/down control; the clear function is substituted for the cascade-in signal in the up/down counter mode. Two 3-input LUTs are used: one generates the counter data, and the other generates the fast carry bit. Synchronous loading is provided by a 2-to-1 multiplexer, and the output of this multiplexer is `AND`ed with a synchronous clear.

Figure 7. FLEX 8000 LE Asynchronous Clear & Preset Modes

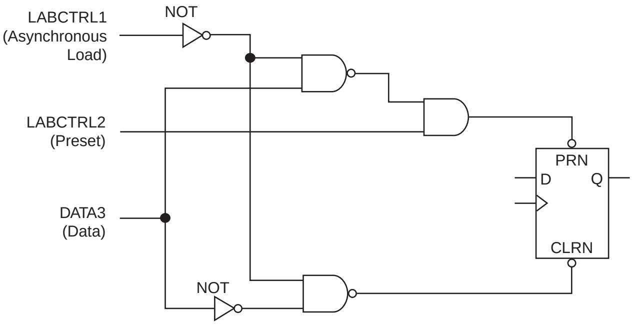
Asynchronous Clear **Asynchronous Preset** **Asynchronous Clear & Preset**



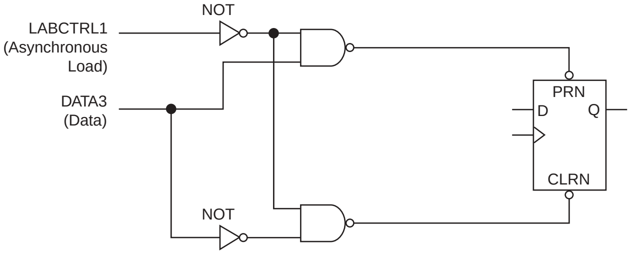
Asynchronous Load with Clear



Asynchronous Load with Preset



Asynchronous Load without Clear or Preset

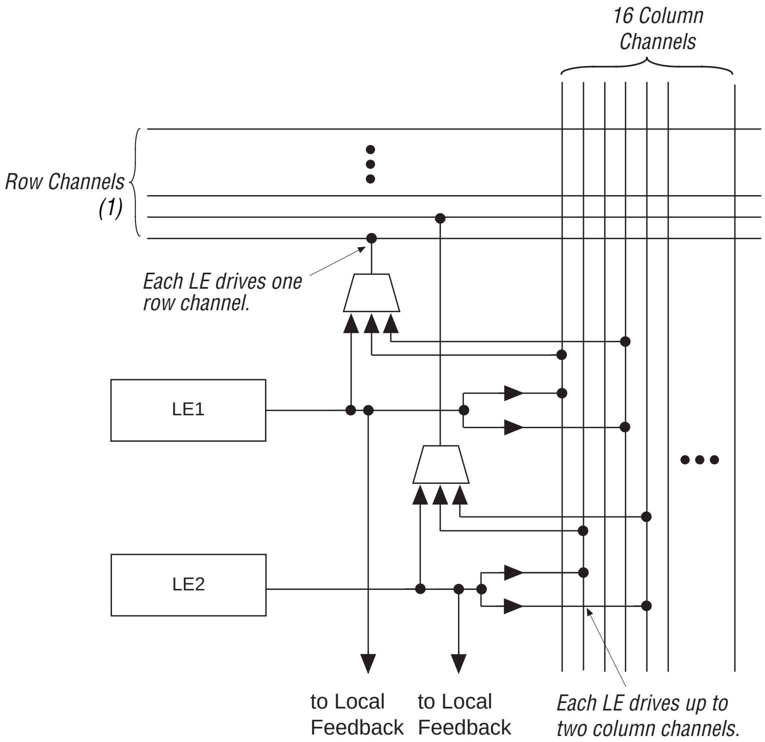


FastTrack Interconnect

In the FLEX 8000 architecture, connections between LEs and device I/O pins are provided by the FastTrack Interconnect, a series of continuous horizontal (row) and vertical (column) routing channels that traverse the entire FLEX 8000 device. This device-wide routing structure provides predictable performance even in complex designs. In contrast, the segmented routing structure in FPGAs requires switch matrices to connect a variable number of routing paths, which increases the delays between logic resources and reduces performance.

The LABs within FLEX 8000 devices are arranged into a matrix of columns and rows. Each row of LABs has a dedicated row interconnect that routes signals both into and out of the LABs in the row. The row interconnect can then drive I/O pins or feed other LABs in the device. Figure 8 shows how an LE drives the row and column interconnect.

Figure 8. FLEX 8000 LAB Connections to Row & Column Interconnect



Note:
(1) See Table 4 for the number of row channels.

Each LE in an LAB can drive up to two separate column interconnect channels. Therefore, all 16 available column channels can be driven by the LAB. The column channels run vertically across the entire device, and share access to LABs in the same column but in different rows. The MAX+PLUS II Compiler chooses which LEs must be connected to a column channel. A row interconnect channel can be fed by the output of the LE or by two column channels. These three signals feed a multiplexer that connects to a specific row channel. Each LE is connected to one 3-to-1 multiplexer. In an LAB, the multiplexers provide all 16 column channels with access to 8 row channels.

Each column of LABs has a dedicated column interconnect that routes signals out of the LABs into the column. The column interconnect can then drive I/O pins or feed into the row interconnect to route the signals to other LABs in the device. A signal from the column interconnect, which can be either the output of an LE or an input from an I/O pin, must transfer to the row interconnect before it can enter an LAB. Table 4 summarizes the FastTrack Interconnect resources available in each FLEX 8000 device.

Table 4. FLEX 8000 FastTrack Interconnect Resources

Device	Rows	Channels per Row	Columns	Channels per Column
EPF8282A EPF8282AV	2	168	13	16
EPF8452A	2	168	21	16
EPF8636A	3	168	21	16
EPF8820A	4	168	21	16
EPF81188A	6	168	21	16
EPF81500A	6	216	27	16

Figure 9 shows the interconnection of four adjacent LABs, with row, column, and local interconnects, as well as the associated cascade and carry chains.

Table 5 lists the source of the peripheral control signal for each FLEX 8000 device by row.

Table 5. Row Sources of FLEX 8000 Peripheral Control Signals

Peripheral Control Signal	EPF8282A EPF8282AV	EPF8452A	EPF8636A	EPF8820A	EPF81188A	EPF81500A
`CLK0`	Row A	Row A	Row A	Row A	Row E	Row E
`CLK1/OE1`	Row B	Row B	Row C	Row C	Row B	Row B
`CLR0`	Row A	Row A	Row B	Row B	Row F	Row F
`CLR1/OE0`	Row B	Row B	Row C	Row D	Row C	Row C
`OE2`	Row A	Row A	Row A	Row A	Row D	Row A
`OE3`	Row B	Row B	Row B	Row B	Row A	Row A
`OE4`	–	–	–	–	–	Row B
`OE5`	–	–	–	–	–	Row C
`OE6`	–	–	–	–	–	Row D
`OE7`	–	–	–	–	–	Row D
`OE8`	–	–	–	–	–	Row E
`OE9`	–	–	–	–	–	Row F

Output Configuration

This section discusses slew-rate control and MultiVolt I/O interface operation for FLEX 8000 devices.

Slew-Rate Control

The output buffer in each IOE has an adjustable output slew rate that can be configured for low-noise or high-speed performance. A slow slew rate reduces system noise by slowing signal transitions, adding a maximum delay of 3.5 ns. The slow slew-rate setting affects only the falling edge of a signal. The fast slew rate should be used for speed-critical outputs in systems that are adequately protected against noise. Designers can specify the slew rate on a pin-by-pin basis during design entry or assign a default slew rate to all pins on a global basis.

For more information on high-speed system design, go to *Application Note 75 (High-Speed Board Designs)*.

The instruction register length for FLEX 8000 devices is three bits. Table 7 shows the boundary-scan register length for FLEX 8000 devices.

Table 7. FLEX 8000 Boundary-Scan Register Length

Device	Boundary-Scan Register Length
EPF8282A, EPF8282AV	273
EPF8636A	417
EPF8820A	465
EPF81500A	645

FLEX 8000 devices that support JTAG include weak pull-ups on the JTAG pins. Figure 14 shows the timing requirements for the JTAG signals.

Figure 14. EPF8282A, EPF8282AV, EPF8636A, EPF8820A & EPF81500A JTAG Waveforms

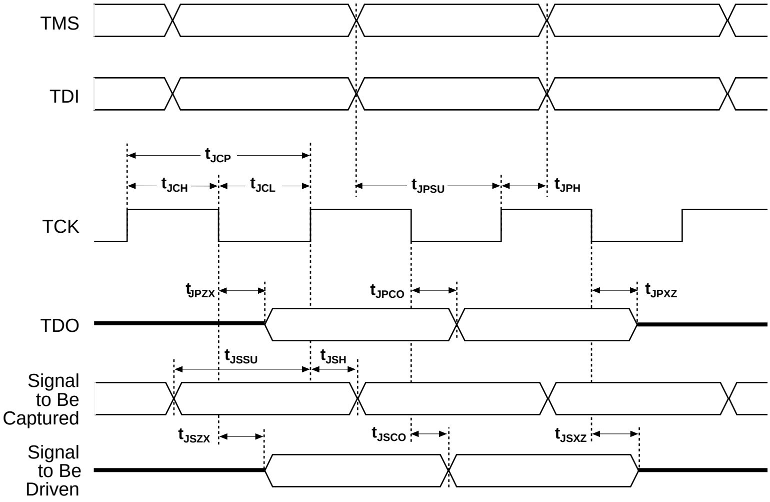


Table 8 shows the timing parameters and values for EPF8282A, EPF8282AV, EPF8636A, EPF8820A, and EPF81500A devices.

Table 12. FLEX 8000 5.0-V Device Capacitance *Note (8)*					
Symbol	**Parameter**	**Conditions**	**Min**	**Max**	**Unit**
C_{IN}	Input capacitance	V_{IN} = 0 V, f = 1.0 MHz		10	pF
C_{OUT}	Output capacitance	V_{OUT} = 0 V, f = 1.0 MHz		10	pF

Notes to tables:

(1) See the *Operating Requirements for Altera Devices Data Sheet*.
(2) Minimum DC input is –0.5 V. During transitions, the inputs may undershoot to –2.0 V or overshoot to 7.0 V for input currents less than 100 mA and periods shorter than 20 ns.
(3) The maximum V_{CC} rise time is 100 ms.
(4) Numbers in parentheses are for industrial-temperature-range devices.
(5) Typical values are for T_A = 25° C and V_{CC} = 5.0 V.
(6) These values are specified in Table 10 on page 28.
(7) The I_{OH} parameter refers to high-level TTL or CMOS output current; the I_{OL} parameter refers to low-level TTL or CMOS output current.
(8) Capacitance is sample-tested only.

Tables 13 through 16 provide information on absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for 3.3-V FLEX 8000 devices.

Table 13. FLEX 8000 3.3-V Device Absolute Maximum Ratings *Note (1)*					
Symbol	**Parameter**	**Conditions**	**Min**	**Max**	**Unit**
V_{CC}	Supply voltage	With respect to ground *(2)*	–2.0	5.3	V
V_I	DC input voltage		–2.0	5.3	V
I_{OUT}	DC output current, per pin		–25	25	mA
T_{STG}	Storage temperature	No bias	–65	150	° C
T_{AMB}	Ambient temperature	Under bias	–65	135	° C
T_J	Junction temperature	Plastic packages, under bias		135	° C

Table 14. FLEX 8000 3.3-V Device Recommended Operating Conditions					
Symbol	**Parameter**	**Conditions**	**Min**	**Max**	**Unit**
V_{CC}	Supply voltage	*(3)*	3.0	3.6	V
V_I	Input voltage		–0.3	V_{CC} + 0.3	V
V_O	Output voltage		0	V_{CC}	V
T_A	Operating temperature	For commercial use	0	70	° C
t_R	Input rise time			40	ns
t_F	Input fall time			40	ns

Table 15. FLEX 8000 3.3-V Device DC Operating Conditions *Note (4)*

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{IH}	High-level input voltage		2.0		V_{CC} + 0.3	V
V_{IL}	Low-level input voltage		–0.3		0.8	V
V_{OH}	High-level output voltage	I_{OH} = –0.1 mA DC *(5)*	V_{CC} – 0.2			V
V_{OL}	Low-level output voltage	I_{OL} = 4 mA DC *(5)*			0.45	V
I_I	Input leakage current	V_I = V_{CC} or ground	–10		10	µA
I_{OZ}	Tri-state output off-state current	V_O = V_{CC} or ground	–40		40	µA
I_{CC0}	V_{CC} supply current (standby)	V_I = ground, no load *(6)*		0.3	10	mA

Table 16. FLEX 8000 3.3-V Device Capacitance *Note (7)*

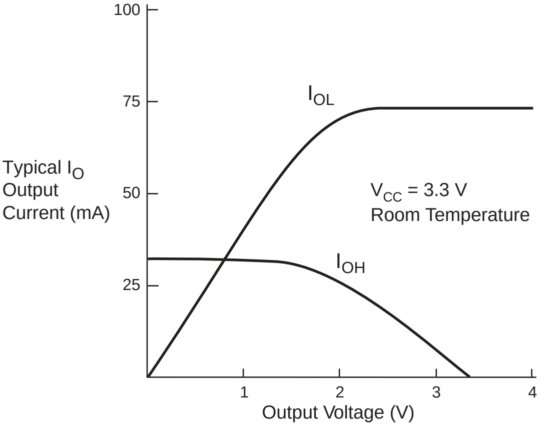
Symbol	Parameter	Conditions	Min	Max	Unit
C_{IN}	Input capacitance	V_{IN} = 0 V, f = 1.0 MHz		10	pF
C_{OUT}	Output capacitance	V_{OUT} = 0 V, f = 1.0 MHz		10	pF

Notes to tables:

(1) See the *Operating Requirements for Altera Devices Data Sheet*.
(2) Minimum DC input voltage is –0.3 V. During transitions, the inputs may undershoot to –2.0 V or overshoot to 5.3 V for input currents less than 100 mA and periods shorter than 20 ns.
(3) The maximum V_{CC} rise time is 100 ms. V_{CC} must rise monotonically.
(4) These values are specified in Table 14 on page 29.
(5) The I_{OH} parameter refers to high-level TTL output current; the I_{OL} parameter refers to low-level TTL output current.
(6) Typical values are for T_A = 25° C and V_{CC} = 3.3 V.
(7) Capacitance is sample-tested only.

Figure 16 shows the typical output drive characteristics of 5.0-V FLEX 8000 devices. The output driver is compliant with ***PCI Local Bus Specification, Revision 2.2***.

Figure 18. Output Drive Characteristics of EPF8282AV Devices



Timing Model

The continuous, high-performance FastTrack Interconnect routing structure ensures predictable performance and accurate simulation and timing analysis. This predictable performance contrasts with that of FPGAs, which use a segmented connection scheme and hence have unpredictable performance. Timing simulation and delay prediction are available with the MAX+PLUS II Simulator and Timing Analyzer, or with industry-standard EDA tools. The Simulator offers both pre-synthesis functional simulation to evaluate logic design accuracy and post-synthesis timing simulation with 0.1-ns resolution. The Timing Analyzer provides point-to-point timing delay information, setup and hold time prediction, and device-wide performance analysis.

Tables 17 through 20 describe the FLEX 8000 timing parameters and their symbols.

Table 19. FLEX 8000 Interconnect Timing Parameters *Note (1)*

Symbol	Parameter
$t_{LABCASC}$	Cascade delay between LEs in different LABs
$t_{LABCARRY}$	Carry delay between LEs in different LABs
t_{LOCAL}	LAB local interconnect delay
t_{ROW}	Row interconnect routing delay *(4)*
t_{COL}	Column interconnect routing delay
t_{DIN_C}	Dedicated input to LE control delay
t_{DIN_D}	Dedicated input to LE data delay *(4)*
t_{DIN_IO}	Dedicated input to IOE control delay

Table 20. FLEX 8000 External Reference Timing Characteristics *Note (5)*

Symbol	Parameter
$\mathbf{t_{DRR}}$	Register-to-register delay via 4 LEs, 3 row interconnects, and 4 local interconnects *(6)*
$\mathbf{t_{ODH}}$	Output data hold time after clock *(7)*

Notes to tables:

(1) Internal timing parameters cannot be measured explicitly. They are worst-case delays based on testable and external parameters specified by Altera. Internal timing parameters should be used for estimating device performance. Post-compilation timing simulation or timing analysis is required to determine actual worst-case performance.

(2) These values are specified in Table 10 on page 28 or Table 14 on page 29.

(3) For the t_{OD3} and t_{ZX3} parameters, V_{CCIO} = 3.3 V or 5.0 V.

(4) The t_{ROW} and t_{DIN_D} delays are worst-case values for typical applications. Post-compilation timing simulation or timing analysis is required to determine actual worst-case performance.

(5) External reference timing characteristics are factory-tested, worst-case values specified by Altera. A representative subset of signal paths is tested to approximate typical device applications.

(6) For more information on test conditions, see *Application Note 76 (Understanding FLEX 8000 Timing)*.

(7) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies to global and non-global clocking, and for LE and I/O element registers.

The FLEX 8000 timing model shows the delays for various paths and functions in the circuit. See Figure 19. This model contains three distinct parts: the LE; the IOE; and the interconnect, including the row and column FastTrack Interconnect, LAB local interconnect, and carry and cascade interconnect paths. Each parameter shown in Figure 19 is expressed as a worst-case value in Tables 22 through 49. Hand-calculations that use the FLEX 8000 timing model and these timing parameters can be used to estimate FLEX 8000 device performance. Timing simulation or timing analysis after compilation is required to determine the final worst-case performance. Table 21 summarizes the interconnect paths shown in Figure 19.

For more information on timing parameters, go to *Application Note 76 (Understanding FLEX 8000 Timing)*.

Table 26. EPF8282AV I/O Element Timing Parameters

Symbol	Speed Grade				Unit
	A-3		A-4		
	Min	Max	Min	Max	
t_{IOD}		0.9		2.2	ns
t_{IOC}		1.9		2.0	ns
t_{IOE}		1.9		2.0	ns
t_{IOCO}		1.0		2.0	ns
t_{IOCOMB}		0.1		0.0	ns
t_{IOSU}	1.8		2.8		ns
t_{IOH}	0.0		0.2		ns
t_{IOCLR}		1.2		2.3	ns
t_{IN}		1.7		3.4	ns
t_{OD1}		1.7		4.1	ns
t_{OD2}		–		–	ns
t_{OD3}		5.2		7.1	ns
t_{XZ}		1.8		4.3	ns
t_{ZX1}		1.8		4.3	ns
t_{ZX2}		–		–	ns
t_{ZX3}		5.3		8.3	ns

Table 27. EPF8282AV Interconnect Timing Parameters

Symbol	Speed Grade				Unit
	A-3		A-4		
	Min	Max	Min	Max	
$t_{LABCASC}$		0.4		1.3	ns
$t_{LABCARRY}$		0.4		0.8	ns
t_{LOCAL}		0.8		1.5	ns
t_{ROW}		4.2		6.3	ns
t_{COL}		2.5		3.8	ns
t_{DIN_C}		5.5		8.0	ns
t_{DIN_D}		7.2		10.8	ns
t_{DIN_IO}		5.5		9.0	ns

Table 28. EPF8282AV Logic Element Timing Parameters

Symbol	Speed Grade				Unit
	A-3		A-4		
	Min	Max	Min	Max	
t_{LUT}		3.2		7.3	ns
t_{CLUT}		0.0		1.4	ns
t_{RLUT}		1.5		5.1	ns
t_{GATE}		0.0		0.0	ns
t_{CASC}		0.9		2.8	ns
t_{CICO}		0.6		1.5	ns
t_{CGEN}		0.7		2.2	ns
t_{CGENR}		1.5		3.7	ns
t_{C}		2.5		4.7	ns
t_{CH}	4.0		6.0		ns
t_{CL}	4.0		6.0		ns
t_{CO}		0.6		0.9	ns
t_{COMB}		0.6		0.9	ns
t_{SU}	1.2		2.4		ns
t_{H}	1.5		4.6		ns
t_{PRE}		0.8		1.3	ns
t_{CLR}		0.8		1.3	ns

Table 29. EPF8282AV External Timing Parameters

Symbol	Speed Grade				Unit
	A-3		A-4		
	Min	Max	Min	Max	
t_{DRR}		24.8		50.1	ns
t_{ODH}	1.0		1.0		ns

Table 30. EPF8452A I/O Element Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{IOD}		0.7		0.8		0.9	ns
t_{IOC}		1.7		1.8		1.9	ns
t_{IOE}		1.7		1.8		1.9	ns
t_{IOCO}		1.0		1.0		1.0	ns
t_{IOCOMB}		0.3		0.2		0.1	ns
t_{IOSU}	1.4		1.6		1.8		ns
t_{IOH}	0.0		0.0		0.0		ns
t_{IOCLR}		1.2		1.2		1.2	ns
t_{IN}		1.5		1.6		1.7	ns
t_{OD1}		1.1		1.4		1.7	ns
t_{OD2}		–		–		–	ns
t_{OD3}		4.6		4.9		5.2	ns
t_{XZ}		1.4		1.6		1.8	ns
t_{ZX1}		1.4		1.6		1.8	ns
t_{ZX2}		–		–		–	ns
t_{ZX3}		4.9		5.1		5.3	ns

Table 31. EPF8452A Interconnect Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
$t_{LABCASC}$		0.3		0.4		0.4	ns
$t_{LABCARRY}$		0.3		0.4		0.4	ns
t_{LOCAL}		0.5		0.5		0.7	ns
t_{ROW}		5.0		5.0		5.0	ns
t_{COL}		3.0		3.0		3.0	ns
t_{DIN_C}		5.0		5.0		5.5	ns
t_{DIN_D}		7.0		7.0		7.5	ns
t_{DIN_IO}		5.0		5.0		5.5	ns

Table 32. EPF8452A LE Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{LUT}		2.0		2.3		3.0	ns
t_{CLUT}		0.0		0.2		0.1	ns
t_{RLUT}		0.9		1.6		1.6	ns
t_{GATE}		0.0		0.0		0.0	ns
t_{CASC}		0.6		0.7		0.9	ns
t_{CICO}		0.4		0.5		0.6	ns
t_{CGEN}		0.4		0.9		0.8	ns
t_{CGENR}		0.9		1.4		1.5	ns
t_{C}		1.6		1.8		2.4	ns
t_{CH}	4.0		4.0		4.0		ns
t_{CL}	4.0		4.0		4.0		ns
t_{CO}		0.4		0.5		0.6	ns
t_{COMB}		0.4		0.5		0.6	ns
t_{SU}	0.8		1.0		1.1		ns
t_{H}	0.9		1.1		1.4		ns
t_{PRE}		0.6		0.7		0.8	ns
t_{CLR}		0.6		0.7		0.8	ns

Table 33. EPF8452A External Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{DRR}		16.0		20.0		25.0	ns
t_{ODH}	1.0		1.0		1.0		ns

Table 34. EPF8636A I/O Element Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{IOD}		0.7		0.8		0.9	ns
t_{IOC}		1.7		1.8		1.9	ns
t_{IOE}		1.7		1.8		1.9	ns
t_{IOCO}		1.0		1.0		1.0	ns
t_{IOCOMB}		0.3		0.2		0.1	ns
t_{IOSU}	1.4		1.6		1.8		ns
t_{IOH}	0.0		0.0		0.0		ns
t_{IOCLR}		1.2		1.2		1.2	ns
t_{IN}		1.5		1.6		1.7	ns
t_{OD1}		1.1		1.4		1.7	ns
t_{OD2}		1.6		1.9		2.2	ns
t_{OD3}		4.6		4.9		5.2	ns
t_{XZ}		1.4		1.6		1.8	ns
t_{ZX1}		1.4		1.6		1.8	ns
t_{ZX2}		1.9		2.1		2.3	ns
t_{ZX3}		4.9		5.1		5.3	ns

Table 35. EPF8636A Interconnect Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
$t_{LABCASC}$		0.3		0.4		0.4	ns
$t_{LABCARRY}$		0.3		0.4		0.4	ns
t_{LOCAL}		0.5		0.5		0.7	ns
t_{ROW}		5.0		5.0		5.0	ns
t_{COL}		3.0		3.0		3.0	ns
t_{DIN_C}		5.0		5.0		5.5	ns
t_{DIN_D}		7.0		7.0		7.5	ns
t_{DIN_IO}		5.0		5.0		5.5	ns

Table 40. EPF8820A LE Timing Parameters

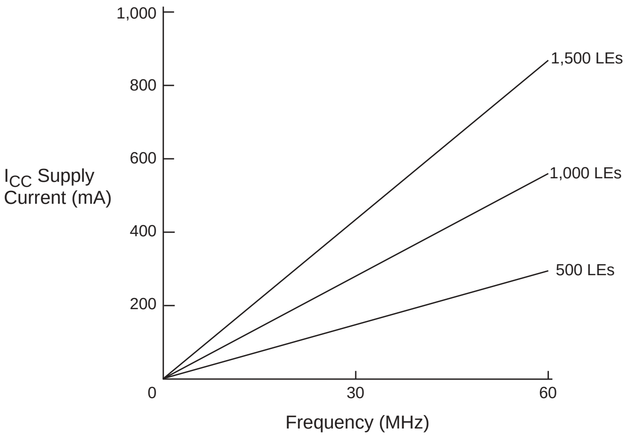
Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{LUT}		2.0		2.5		3.2	ns
t_{CLUT}		0.0		0.0		0.0	ns
t_{RLUT}		0.9		1.1		1.5	ns
t_{GATE}		0.0		0.0		0.0	ns
t_{CASC}		0.6		0.7		0.9	ns
t_{CICO}		0.4		0.5		0.6	ns
t_{CGEN}		0.4		0.5		0.7	ns
t_{CGENR}		0.9		1.1		1.5	ns
t_C		1.6		2.0		2.5	ns
t_{CH}	4.0		4.0		4.0		ns
t_{CL}	4.0		4.0		4.0		ns
t_{CO}		0.4		0.5		0.6	ns
t_{COMB}		0.4		0.5		0.6	ns
t_{SU}	0.8		1.1		1.2		ns
t_H	0.9		1.1		1.5		ns
t_{PRE}		0.6		0.7		0.8	ns
t_{CLR}		0.6		0.7		0.8	ns

Table 41. EPF8820A External Timing Parameters

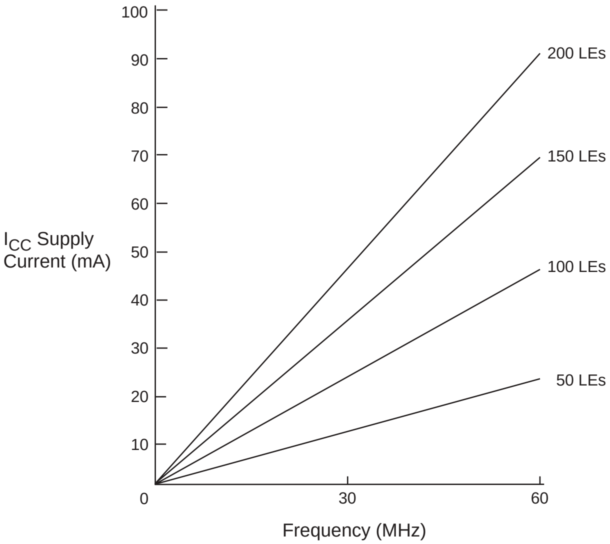
Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
$\mathbf{t_{DRR}}$		16.0		20.0		25.0	ns
$\mathbf{t_{ODH}}$	1.0		1.0		1.0		ns

Figure 20. FLEX 8000 $I_{CCACTIVE}$ vs. Operating Frequency

5.0-V FLEX 8000 Devices



3.3-V FLEX 8000 Devices



Configuration & Operation

The FLEX 8000 architecture supports several configuration schemes to load a design into the device(s) on the circuit board. This section summarizes the device operating modes and available device configuration schemes.

For more information, go to *Application Note 33 (Configuring FLEX 8000 Devices)* and *Application Note 38 (Configuring Multiple FLEX 8000 Devices)*.

Operating Modes

The FLEX 8000 architecture uses SRAM elements that require configuration data to be loaded whenever the device powers up and begins operation. The process of physically loading the SRAM programming data into the device is called *configuration*. During initialization, which occurs immediately after configuration, the device resets registers, enables I/O pins, and begins to operate as a logic device. The I/O pins are tri-stated during power-up, and before and during configuration. The configuration and initialization processes together are called *command mode*; normal device operation is called *user mode*.

SRAM elements allow FLEX 8000 devices to be reconfigured in-circuit with new programming data that is loaded into the device. Real-time reconfiguration is performed by forcing the device into command mode with a device pin, loading different programming data, reinitializing the device, and resuming user-mode operation. The entire reconfiguration process requires less than 100 ms and can be used to dynamically reconfigure an entire system. In-field upgrades can be performed by distributing new configuration files.

Configuration Schemes

The configuration data for a FLEX 8000 device can be loaded with one of six configuration schemes, chosen on the basis of the target application. Both active and passive schemes are available. In the active configuration schemes, the FLEX 8000 device functions as the controller, directing the loading operation, controlling external configuration devices, and completing the loading process. The clock source for all active configuration schemes is an oscillator on the FLEX 8000 device that operates between 2 MHz and 6 MHz. In the passive configuration schemes, an external controller guides the FLEX 8000 device. Table 51 shows the data source for each of the six configuration schemes.

Table 51. Data Source for Configuration

Configuration Scheme	Acronym	Data Source
Active serial	AS	Altera configuration device
Active parallel up	APU	Parallel configuration device
Active parallel down	APD	Parallel configuration device
Passive serial	PS	Serial data path
Passive parallel synchronous	PPS	Intelligent host
Passive parallel asynchronous	PPA	Intelligent host

Table 53. FLEX 8000 160-, 192- & 208-Pin Package Pin-Outs (Part 2 of 2)

Pin Name	160-Pin PQFP EPF8452A	160-Pin PQFP EPF8636A	192-Pin PGA EPF8636A EPF8820A	208-Pin PQFP EPF8636A *(1)*	208-Pin PQFP EPF8820A *(1)*	208-Pin PQFP EPF81188A *(1)*
`DATA4`	154	127	E17	165	172	170
`DATA3`	157	124	G15	162	171	168
`DATA2`	159	122	F15	160	167	166
`DATA1`	11	115	E16	149	165	163
`DATA0`	12	113	C16	147	162	161
`SDOUT` *(3)*	128	152	C7 *(11)*	198	124	119
`TDI` *(4)*	–	55	R11	72	20	–
`TDO` *(4)*	–	95	B9	120	129	–
`TCK` *(4)*, *(6)*	–	57	U8	74	30	–
`TMS` *(4)*	–	59	U7	76	32	–
`TRST` *(7)*	–	40	R3	54	54	–
Dedicated Inputs *(10)*	5, 36, 85, 116	6, 35, 87, 116	A5, U5, U13, A13	7, 45, 112, 150	17, 36, 121, 140	13, 41, 116, 146
`VCCINT` (5.0 V)	21, 41, 53, 67, 80, 81, 100, 121, 133, 147, 160	4, 5, 26, 85, 106	C8, C9, C10, R8, R9, R10, R14	5, 6, 33, 110, 137	5, 6, 27, 48, 119, 141	4, 20, 35, 48, 50, 102, 114, 131, 147
`VCCIO` (5.0 V or 3.3 V)	–	25, 41, 60, 70, 80, 107, 121, 140, 149, 160	D3, D4, D9, D14, D15, G4, G14, L4, L14, P4, P9, P14	32, 55, 78, 91, 102, 138, 159, 182, 193, 206	26, 55, 69, 87, 102, 131, 159, 173, 191, 206	3, 19, 34, 49, 69, 87, 106, 123, 140, 156, 174, 192
`GND`	13, 14, 28, 46, 60, 75, 93, 107, 108, 126, 140, 155	15, 16, 36, 37, 45, 51, 75, 84, 86, 96, 97, 117, 126, 131, 154	C4, D7, D8, D10, D11, H4, H14, K4, K14, P7, P8, P10, P11	19, 20, 46, 47, 60, 67, 96, 109, 111, 124, 125, 151, 164, 171, 200	15, 16, 37, 38, 60, 78, 96, 109, 110, 120, 130, 142, 152, 164, 182, 200	11, 12, 27, 28, 42, 43, 60, 78, 96, 105, 115, 122, 132, 139, 148, 155, 159, 165, 183, 201
No Connect (N.C.)	2, 3, 38, 39, 70, 82, 83, 118, 119, 148	2, 39, 82, 119	C6, C12, C13, C14, E3, E15, F3, J3, J4, J14, J15, N3, N15, P3, P15, R4 *(12)*	1, 2, 3, 16, 17, 18, 25, 26, 27, 34, 35, 36, 50, 51, 52, 53, 104, 105, 106, 107, 121, 122, 123, 130, 131, 132, 139, 140, 141, 154, 155, 156, 157, 208	1, 2, 3, 50, 51, 52, 53, 104, 105, 106, 107, 154, 155, 156, 157, 208	1, 2, 51, 52, 53, 54, 103, 104, 157, 158, 207, 208
Total User I/O Pins *(9)*	116	114	132, 148 *(13)*	132	148	144

Notes to tables:

(1) Perform a complete thermal analysis before committing a design to this device package. See *Application Note 74 (Evaluating Power for Altera Devices)* for more information.
(2) This pin is a dedicated pin and is not available as a user I/O pin.
(3) `SDOUT` will drive out during configuration. After configuration, it may be used as a user I/O pin. By default, the MAX+PLUS II software will not use `SDOUT` as a user I/O pin; the user can override the MAX+PLUS II software and use `SDOUT` as a user I/O pin.
(4) If the device is not configured to use the JTAG BST circuitry, this pin is available as a user I/O pin.
(5) JTAG pins are available for EPF8636A devices only. These pins are dedicated user I/O pins.
(6) If this pin is used as an input in user mode, ensure that it does not toggle before or during configuration.
(7) `TRST` is a dedicated input pin for JTAG use. This pin must be grounded if JTAG BST is not used.
(8) Pin 52 is a V_{CC} pin on EPF8452A devices only.
(9) The user I/O pin count includes dedicated input pins and all I/O pins.
(10) Unused dedicated inputs should be tied to ground on the board.
(11) `SDOUT` does not exist in the EPF8636GC192 device.
(12) These pins are no connect (N.C.) pins for EPF8636A devices only. They are user I/O pins in EPF8820A devices.
(13) EPF8636A devices have 132 user I/O pins; EPF8820A devices have 148 user I/O pins.
(14) For EPF81500A devices, these pins are dedicated JTAG pins and are not available as user I/O pins. If JTAG BST is not used, `TDI`, `TCK`, `TMS`, and `TRST` should be tied to `GND`.

Revision History

The information contained in the *FLEX 8000 Programmable Logic Device Family Data Sheet* version 11.1 supersedes information published in previous versions. The *FLEX 8000 Programmable Logic Device Family Data Sheet* version 11.1 contains the following change: minor textual updates.